

<i>Notice of References Cited</i>	Application/Control No. 10/580,401	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner MEWALE AMBAYE	Art Unit 4124	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-7,215,640	05-2007	Matsubara, Daisuke	370/235
*	C	US-2006/0182127	08-2006	Park, Ki-Beom	370/400
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	M	US-			

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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